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RESEARCH ARTICLE

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Electrical Force Emission AVO meter - Function Generator- Spectrum Analyzer - Dc Power supply

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I. Introduction

The development of labs is one of the goals of the educational system that include the occupational safety and health standards and we choose the Electrical Force emission as my research by choosing the data from three different to represent the sample in my research that I can distribute the result the other labs. The research useful for the teacher and trainer to apply the development the labs within educational program include the safety and health standard to reduce the Electrical force in our labs.

Target:

- 1. The laboratory safeties are a part of the education systems.
- 2. Opening the new area to the trainer and engineering to participate the fundamental structure of the labs is considered as a main part of labs experience.
- 3. Gives the suggestion to how the reduce the Electrical Force in the labs.
- 4. To know if any failure performs in the labs.
- 5. Apply the training program into available Electrical Force measuring device on the labs.
- 6. The new device should be agreeing with Electrical Force safety only.
- 7. Teaching howe to measure the Electrical Force
- 8. Apply the short training program about the safety of Electrical Force

Summary:

The research target is to reduce the Electrical force by choosing the samples of electronics labs include deferent number of devices and use the Electrical Force measuring device and use the standard value.

My research question is:

If there any devices in the labs the Electrical force succeeded the standard value? and haw can be treated with these devises? and what should be the action? and what the procedure should be taken to improve the labs according to the research result? and what is the suggestion can be given

Sample surveys:

We choose the devices from three different labs collected in one table represent 109.

Survey instrument & Statistical analysis

- 1. Electrical force instrument meter
- 2. Temperature instrument meter
- 3. Distance instrument meter
- 4. Observational from research

Result and recommendation:

The Function Generator is most the device exceeded the standard Electrical Force value and reach 24.7% from the total device, and DC Power supply is the least devices exceeded the Electrical Force standard value 9.1%, from total device the recommendation is re- examination these devise again because its exceed the Electrical force standard value.

Also, specify the number of students at each table, and raise the congestion of devices inside the labs spacing between devices reformulation of experiments to reduce the Electrical Force waves while preserving the scientific material, use the Lab simulation as one of the alternatives available to reduce the Electrical Force of waves during the performance of the scientific experiment.

The Standard:

The standard is 38.83 V/m.

Data collection method : Devices:

- DC Power (analogue)
- DC Power (digital)
- AVO
- Function Generator

- Spectrum Analyzer

- Oscilloscope

Then the arithmetic mean of the Electrical Force wave reading was taken; the temperature and the principle of the temperature measured for all devices and in the sample laboratories used.

Sample volume:

The sample size was 109 samples.

Answering the research questions:

After taking the results from the sample of the study and in view of the standard that was determined, it constitutes a violation of what is permitted? after observing the table we conclude the following:

1. The most type of device that exceeded the standard is the (Function Generator) device, which was 24.7% from total device

2. While the lowest percentage was (DC Power Supply Digital) 9.1%

3. There is no direct relationship with the increase in the average temperature of the laboratory and the increase from the standard level of Electrical Force waves, as shown in Table (2)

4. When measuring the Electrical Force emitted from electrical panels (DB), no more than the specified standard was recorded as shown in the table.

5. Exposing the devices to sunlight for long periods and the deficiency of protection from its light inside the laboratory contributed to the speedy damage of some devices and put them out of use.

The most important findings and recommendations:

- spacing between devices and tables is importunate to reduce the Electrical force

- Redesigned experiment tables that increase space available.

- Redistribute the devices between the experimental tables, the model.

- Remove high-risk devices from laboratories (AC Transformer) for not being used in experiments so that they do not pose a danger to users

- Re-examine and evaluate the efficiency of the device, devices in which the standard ratio of Electrical Force

- Redesigning laboratory experiments in accordance with the specified standard, in a way that allows to reduce the number of devices used and without prejudice to the scientific material

- Using the technology of merging devices into one training board.

- Benefiting from Lab simulator, which is based on simulation technology

trainer can determine whether the emitted waves conform to the specified standard.

- Benefit from the expertise of the Radiation Protection Department hold training courses for trainers in the field of Electrical Protection.

-Developing a special indicator of laboratory safety so that it is applied to all laboratories within specific criteria, including temperature, the principle of distance measured by the device used in Electrical Force and the permissible amount of it.

- Replacing laboratory equipment tables with ones dedicated to absorbing Electrical Force

- The width distance of the laboratory table must be directly proportional to the number of students allowed at each laboratory table, by reference to the specifications before purchase, and that the number of students at each laboratory table does not exceed the number allowed.

	Tabl.1						
		La	ıb				
Device	Sample	E.M.F(mg)	Elect.Force(v/m)	Temp °c	Dist. M		
Sp	1	2.1	47	27.9	0.283		
ectru	2	1.3	17	24.2	0.30		
	3	1	0	24.4	0.233		
n A	4	107	3	24.5	0.233		
λnε	5	1	92	23.4	0.350		
aly	6	3.2	30	22.7	0.41		
zer	Mean Value	19.2	31.5	24.5	0.30		

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Tabl.2								
Lab								
Device	Sample	E.M.F(mg)	Elect.Force(v/m)	Temp c°	Dist.			
	1	56.7	11	24.1	0.296			
	2	38.5	18	24.4	0.365			
	3	0.8	34	24.4	0.365			
	4	22.7	26	23.4	0.380			
DC Powe	5	76	3	22.6	0.300			
	6	20	18	22.6	0.450			
Ч.	7	91.5	77	22.5	0.240			
dnç	8	43	29	22.5	0.17			
ply	9	405	16	22.5	0.300			
/(a)	10	48.2	6	23.1	0.350			
nal	11	22.5	18	23.3	0.31			
og	12	40.9	44	17.8	0.350			
ue)	13	19.1	5	17.8	0.350			
	14	35.9	19	17.8	0.350			
	15	24.6	24	17.8	0.350			
	16	19.9	22	17.8	0.350			
	Mean Value	60.3	23.1	21.5	0.32			

ISSN: 2248-9622, Vol. 13, Issue 10, October 2023, pp 150-155

Tabl.3

Lab.							
Device	Sample N0.	E.M.F(mg)	Elect.Force(v/m)	°c Temp.	Dist.		
	1	1.9	44	23.9	0.362		
	2	3.9	22	24.1	0.326		
	3	0.9	20	24.5	0.387		
	4	1.1	0	24.4	0.445		
	5	0.9	2	24.4	0.445		
	6	0.7	0	24.4	0.445		
	7	9.4	23	22.3	0.380		
	8	6.3	2	22.7	0.380		
	9	13.7	14	23.2	0.380		
	10	13.6	18	23.3	0.380		
F	11	10.7	2	23.4	0.380		
uno	12	13	19	23.3	0.380		
ctio	13	3	10	23.8	0.280		
on (14	3.1	27	22.6	0.410		
Gei	15	2.6	31	22.9	0.440		
ıer	16	0.9	96	22.7	0.300		
ato	17	0.6	22	22.5	0.250		
r	18	2.4	37	22.8	0.300		
	19	20	4	23.2	0.410		
	20	3.4	9	23.2	0.340		
	21	6.9	135	20.4	0.320		
	22	0.6	183	18.7	0.350		
	23	9.7	12	18.7	0.350		
	24	0.5	71	18.7	0.350		
	25	0.7	41	18.7	0.350		
	26	0.7	19	18.7	0.350		
	27	9.1	9	18.7	0.350		

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	Mean Value	5.1	32.2	22.2	0.36				
Table.4									
	Lab								
Device	Sample N0	E.M.F(mg)	Elect.Force(v/m)	°c Temp.	M Dist.				
	1	93.5	2	23.2	0.284				
	2	26.4	18	23.6	0.420				
	3	59.95	10	23.4	0.350				
DC	4	71.1	4	23.1	0.330				
Po	5	72.7	19	20.0	0.300				
wer	6	56.8	8	18.2	0.300				
Dig	7	56.7	10	18.2	0.300				
ital	8	60.2	1	18.2	0.300				
	9	90.9	43	18.2	0.300				
	10	62.9	6	18.2	0.300				
	Mean Value	65.1	12.1	20.43	0.31				

ISSN: 2248-9622, Vol. 13, Issue 10, October 2023, pp 150-155

Tabl.5

	Lab							
Device	Sample	E.M.F(mg)	Elect.Force (v/m)	Temp. °c	Dist.			
	1	4.1	3	24.1	0.370			
	2	2.3	78	22.9	0.383			
	3	2.4	14	24.1	0.270			
	4	0.9	10	23.8	0.270			
	5	4.1	5	23.7	0.300			
	6	2.9	8	22.5	0.380			
	7	1.3	14	22.9	0.440			
	8	7.9	2	22.6	0.370			
	9	6.1	10	22.6	0.370			
	10	1.7	1	25.5	0.41			
0	11	2.3	20	22.7	0.410			
sci	12	0.9	21	22.6	0.300			
llos	13	0.6	24	22.6	0.30			
ŝĊO	14	6.1	64	22.8	0.290			
pe	15	1	1	23.1	0.360			
	16	3.5	24	23.1	0.300			
	17	2	9	23.3	0.340			
	18	0.5	40	19.4	0.360			
	19	0.7	4	19.4	0.360			
	20	0.5	30	19.4	0.360			
Ī	21	0.5	7	19.4	0.360			
ſ	22	0.6	1	19.4	0.360			
ſ	23	0.6	5	19.4	0.360			
ſ	24	0.4	47	19.4	0.270			
ľ	Mean Value	2.2	18.4	22.1	0.34			

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	Tabl.6								
	Lab								
Device	Sample	E.M.F(mg)	Elect.Force(v/m)	Temp. °c	Dist.				
	1	3.5	4	23.5	0.285				
	2	42	28	24.1	0.303				
	3	1.9	6	23.6	0.340				
	4	2.5	4	23.7	0.360				
	5	3.7	4	23.7	0.360				
	6	2.4	26	23.6	0.370				
	7	1.5	6	23.5	0.430				
	8	7.9	50	22.6	0.220				
	9	5.3	7	22.6	0.280				
	10	9.4	46	22.9	0.150				
	11	29.9	39	22.9	0.150				
	12	15.1	111	22.9	0.210				
VC	13	8.7	180	22.5	00.22				
	14	10.7	19	22.5	0.240				
ſet	15	8.3	1	22.5	0.240				
er	16	1.8	10	20.4	0.320				
	17	1.9	11	20.0	0.300				
	18	2	17	19.3	0.410				
	19	0.7	38	19.3	0.410				
	20	1.3	3	19.3	0.410				
	21	0.8	6	19.3	0.410				
	22	0.9	8	19.3	0.410				
	23	0.8	4	19.3	0.410				
	24	0.7	23	19.3	0.410				
	25	1.1	96	19.3	0.330				
	26	2.4	17	19.3	0.400				
	Mean Value	6.4	29.3	21.5	0.32				

ISSN: 2248-9622, Vol. 13, Issue 10, October 2023, pp 150-155

Table.7

_		Mean Value			
Device	#	E.M.F (mg)	Elect.Force (v/m)	°Temp c	Dist. M
DC Power (analogue)	16	60.3	23.1	21.5	0.32
DC Power (digital)	10	65.1	12.1	20.43	0.31
AVO	26	6.4	29.3	21.5	0.32
Function Generator	27	5.1	32.2	22.2	0.36
Spectrum Analyzer	6	19.2	31.5	24.5	0.30
Oscilloscope	24	2.2	18.4	22.1	0.34

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					Table.8					
				The nur	The number of devices that exceeded the					
				spe	ecified star	ndard (38.8	3 V∖m)			
					Ele	ct.Force				
% Lab	Tot.Devices	Tot.exceed Devices	Oscilloscope	DC Power Digital	DC Power Analogue	Spectrum Analyzer	Function Generator	AVO meter	Lab	
17.4	109	19	4	1	2	2	5	6		
			16.6	10	12.5	33.3	18.5	23	%	

	Exp.Table	E.M.F(mg)	Elect.Force(v/m)	°c Temp	Device/table
	1	8.1	50	18.1	6
	2	20.1	1	18	5
	3	57.8	42	18.2	3
	4	22.5	42	17.9	7
	5	39.7	46	17.9	11
	6	9.2	34	18	5
	7	45.3	15	18.2	6
	8	2.9	17	18.2	5
	9	53.1	5	18.7	5
	10	39.2	2	18.8	8
L	11	57.3	6	18.8	5
ab	12	39.2	9	18.9	4
	13	77.6	4	18.9	4
	14	46.8	34	20.1	5
	15	40.3	5	19.7	6
	16	10	44	19.3	4
	17	3	4	19	1
	18	57.9	7	18.8	4
	19	8.6	9.6	18.7	2
	20	9.4	35	18.7	4
	21	0.7	8	18.7	4
	Mean Value	32.03	18.4	18.6	5

Tabl.9

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